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DS26C32AMQML

Quad Differential Line Receiver

General Description

The DS26C32A is a quad differential line receiver designed to meet the RS-422, RS-423, and Federal Standards 1020 and 1030 for balanced and unbalanced digital data transmission, while retaining the low power characteristics of CMOS.

The DS26C32A has an input sensitivity of 200 mV over the common mode input voltage range of $\pm 7V$. The DS26C32A features internal pull-up and pull-down resistors which prevent output oscillation on unused channels.

The DS26C32A provides an enable and disable function common to all four receivers, and features TRI-STATE ® outputs

with 6 mA source and sink capability. This product is pin compatible with the DS26LS32A and the AM26LS32.

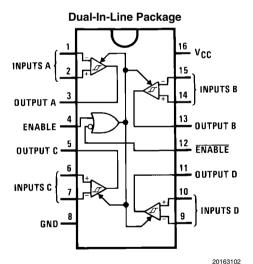
Features

- CMOS design for low power
- ±0.2V sensitivity over input common mode voltage range
- Input fail-safe circuitry.
- Inputs won't load line when V_{CC} = 0V
- Meets the requirements of EIA standard RS-422
- TRI-STATE outputs for connection to system buses

Ordering Information

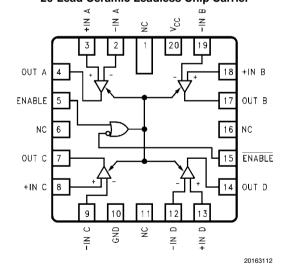
NS Part Number	SMD Part Number	NS Package Number	Package Description
DS26C32AME/883	5962-9164001M2A	E20A	20LD Leadless Chip Carrier
DS26C32AMJ/883	5962-9164001MEA	J16A	16LD Ceramic Dip
DS26C32AMW/883	5962-9164001MFA	W16A	16LD Ceramic Flatpack
DS26C32AMWG/883	5962-9164001MXA	WG16A	16LD Ceramic SOIC

Connection Diagrams



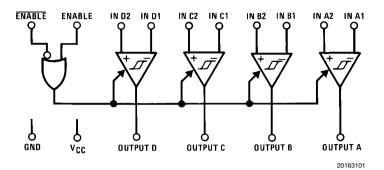
Top View See NS Package J16A, WG16A, or W16A

20-Lead Ceramic Leadless Chip Carrier



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Logic Diagram



Truth Table

ENABLE	ABLE ENABLE Input		Output
L	Н	Х	Z
All Other Combinations of Enable Inputs		$V_{ID} \ge V_{Th} (Max)$	Н
		V _{ID} ≤ V _{Th} (Min)	L
		Open	Н

Z = TRI-STATE

Absolute Maximum Ratings (Note 2, Note 1)

Supply Voltage (V_{CC}) 7V Common Mode Range (V_{CM}) $\pm 14V$ Differential Input Voltage (V_{Diff}) $\pm 14V$ Enable Input Voltage (V_{I}) 7V Storage Temperature Range (T_{Stg}) $-65^{\circ}C \le T_{A} \le +150^{\circ}C$ Lead Temperature (Soldering 4 sec.) 260°C

Recommended Operating Conditions

	Min	Max	Units
Supply Voltage (V _{CC})	4.50	5.50	V
Operating Temperature Range (T _*)	-55	+125	°C

Quality Conformance Inspection

Mil-Std-883, Method 5005 - Group A

Subgroup	Description	Temp °C
1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55
12	Settling time at	+25
13	Settling time at +1	
14	Settling time at	-55

DS26C32AM Electrical Characteristics

DC Parameters

Symbol	Parameter	Conditions	Notes	Min	Max	Units	Sub- groups
V _{TH}	Minimum Differential Input Voltage	$V_{CC} = 5V$, $V_{O} = V_{OH}$ or V_{OL} , -7 < V_{CM} < +7		-200	+200	mV	1, 2, 3
R _I	Input Resistance	$V_{CC} = 5V$, -7 < V_{CM} < +7, One input AC Gnd		4.5	11	ΚΩ	1, 2, 3
I _I	Input Current	$V_{CC} = 5V$, $V_I = +10V$, Other Input = Gnd			+1.8	mA	1, 2, 3
		$V_{CC} = 5V$, $V_I = -10V$, Other Input = Gnd			-2.7	mA	1, 2, 3
V _{OH}	Logical "1" Output Voltage	$V_{CC} = 4.5V, V_{Diff} = +1V,$ $I_{O} = -6.0mA$		3.8		V	1, 2, 3
V _{OL}	Logical "0" Output Voltage	$V_{CC} = 5.5V$, $V_{CC} = Max$, $V_{Diff} = -1V$, $I_{O} = 6.0mA$			0.3	V	1, 2, 3
V _{IH}	Minimum Enable High Level Voltage		(Note 3)	2.0		V	1, 2, 3
V _{IL}	Maximum Enable Low Level Voltage		(Note 3)		0.8	V	1, 2, 3
I _{OZ}	Maximum TRI-STATE Output Leakage Current	$V_O = V_{CC}$ or Gnd, Enable = V_{IL} , Enable = V_{IH}			±5.0	μΑ	1, 2, 3
I _I	Maximum Enable Input Current	V _I = V _{CC} or Gnd			±1.0	μΑ	1, 2, 3
I _{cc}	Quiescent Power Supply Current	$V_{Diff} = +1V, V_{CC} = 5.5V$			25	mA	1, 2, 3

AC Parameters - Propagation Delay Time

The following conditions apply, unless otherwise specified. $V_{CC} = 5V \pm 10\%$, $C_{CL} = 50 pF$, $V_{Diff} = 2.5 V_{CC} = 50 pF$

Symbol	Parameter	Conditions	Notes	Min	Max	Units	Sub- groups
t _{PLH}	Input to Output Prop Delay	V _{CM} = 0V			35	ns	9, 10, 11
t _{PHL}	Input to Output Prop Delay	$V_{CM} = 0V$			35	ns	9, 10, 11
t _{Rise}	Output Rise Time	$V_{CM} = 0V$			9	ns	9, 10, 11
t _{Fall}	Output Fall Time	$V_{CM} = 0V$			9	ns	9, 10, 11
t _{PLZ}	Output Disable Time	$R_L = 1000\Omega$			29	ns	9, 10, 11
t _{PZL}	Output Enable Time	$R_L = 1000\Omega$			29	ns	9, 10, 11
t _{PHZ}	Output Disable Time	$R_L = 1000\Omega$			29	ns	9, 10, 11
t _{PZH}	Output Enable Time	$R_L = 1000\Omega$			29	ns	9, 10, 11

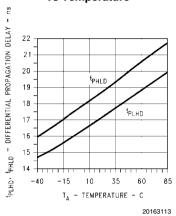
Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 2: Unless otherwise specified, all voltages are referenced to ground.

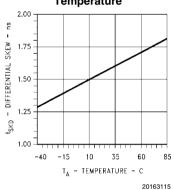
Note 3: Parameter tested Go-No-Go only.

Typical Performance Characteristics

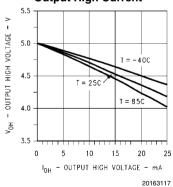
Differential Propagation Delay vs Temperature



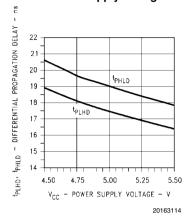
Differential Skew vs Temperature



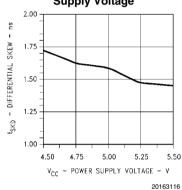
Output High Voltage vs Output High Current



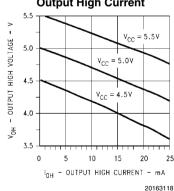
Differential Propagation Delay vs Power Supply Voltage



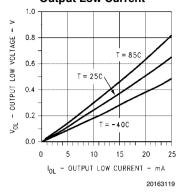
Differential Skew vs Power Supply Voltage



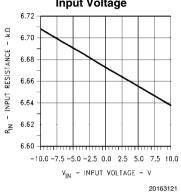
Output High Voltage vs Output High Current



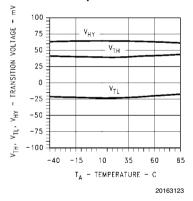
Output Low Voltage vs Output Low Current



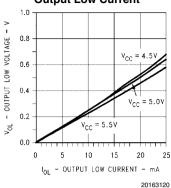
Input Resistance vs Input Voltage



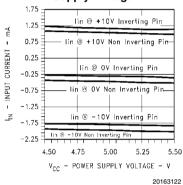
Hysteresis & Differential Transition Voltage vs Temperature



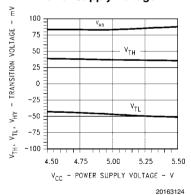
Output Low Voltage vs Output Low Current



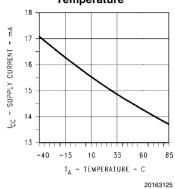
Input Current vs Power Supply Voltage



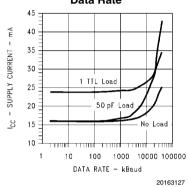
Hysteresis & Differential Transition Voltage vs Power Supply Voltage



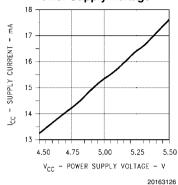
Supply Current vs Temperature



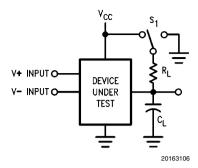
Supply Current vs Data Rate



Disabled Supply Current vs Power Supply Voltage



AC Test Circuit and Switching Time Waveforms



 $\mathbf{C}_{\mathbf{L}}$ includes load and test jig capacitance.

 $S_1 = V_{CC}$ for $_{tPZL}$, and t_{PLZ} measurements.

 $S_1 = Gnd \text{ for } t_{PZH}, \text{ and } t_{PHZ} \text{ measurements.}$

FIGURE 1. Test Circuit for TRI-STATE Output Tests

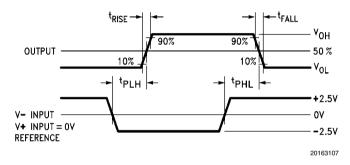


FIGURE 2. Propagation Delay

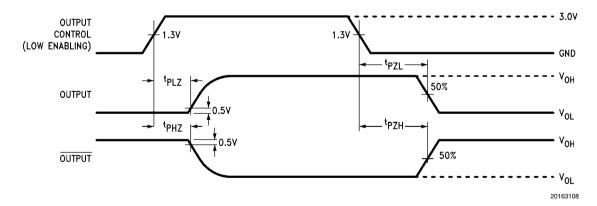
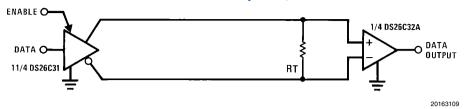


FIGURE 3. TRI-STATE®Output Enable and Disable Waveforms

Typical Applications

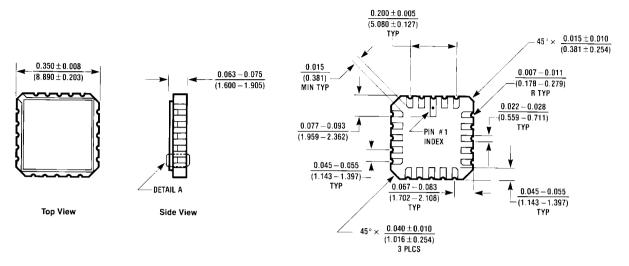
Two-Wire Balanced Systems, RS-422



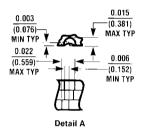
Revision History Section

Released	Revision	Section	Changes
10/26/2010	A	· '	MDS data sheets converted into one Corp. data sheet format. MNDS26C32AM-X Rev 0B0 will be archived.

Physical Dimensions inches (millimeters) unless otherwise noted

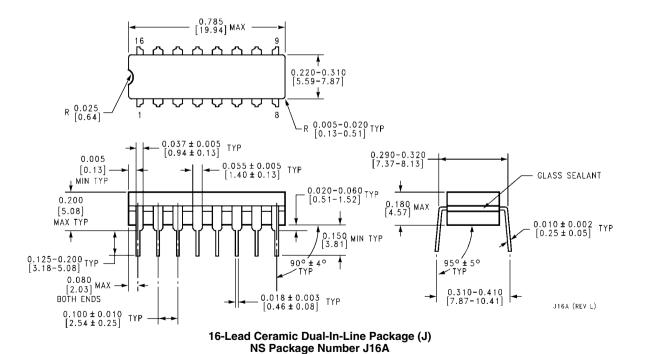


Bottom View

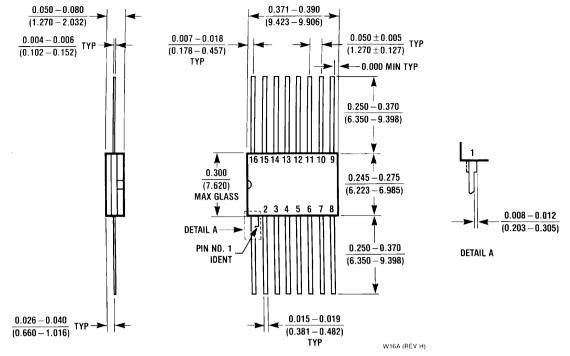


E20A (REVID:

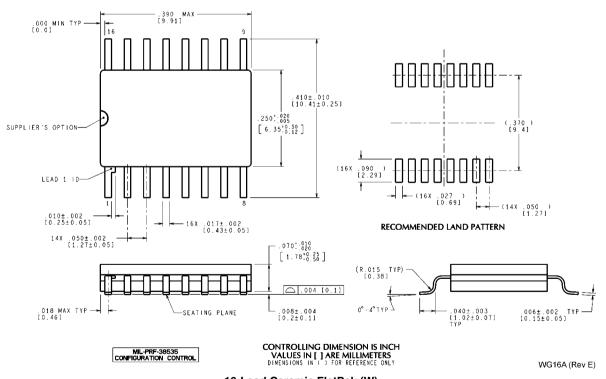
20-Lead Ceramic Leadless Chip Carrier (E) NS Package Number E20A



11



16-Lead Ceramic FlatPak (W) NS Package Number W16A



16-Lead Ceramic FlatPak (W) NS Package Number WG16A

Notes

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Clock and Timing	www.national.com/timing	Reference Designs	www.national.com/refdesigns	
Data Converters	www.national.com/adc	Samples	www.national.com/samples	
Interface	www.national.com/interface	Eval Boards	www.national.com/evalboards	
LVDS	www.national.com/lvds	Packaging	www.national.com/packaging	
Power Management	www.national.com/power	Green Compliance	www.national.com/quality/green	
Switching Regulators	www.national.com/switchers	Distributors	www.national.com/contacts	
LDOs	www.national.com/ldo	Quality and Reliability	www.national.com/quality	
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